



**Setting the Test Standard for
Tomorrow**

Gayn Erickson, CEO

Nasdaq: AEHR

Safe Harbor Statement

This presentation contains forward-looking statements that involve risks and uncertainties relating to projections regarding industry growth and customer demand for the Company's products. Actual results may vary from projected results. These risks and uncertainties include without limitation, acceptance by customers of the ABTSTM and FOXTM technologies, the Company's development and manufacture of a commercially successful wafer-level test and burn-in system, world economic conditions, the timing of the recovery of the semiconductor equipment market, the Company's ability to maintain sufficient cash to support operations, and the potential emergence of alternative technologies, which could adversely affect demand for the Company's products in fiscal year 2014. See the Company's recent 10-K and 10-Q reports filed with the SEC for a more detailed description of the risks facing the Company's business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this presentation.

Aehr Test Systems *(Nasdaq: AEHR)*

Production Semiconductor Test & Burn-in For over 35 Years!

- Technology leader in massively parallel test & burn-in systems with 2,500 systems installed worldwide
- Unique full-wafer test & burn-in systems and contactors
- High parallel wafer level and package test products



**Packaged Part
Test & Burn-in**



**Multiple Wafer
Test & Burn-in**



**Single Wafer
Test & Burn-in**

AEHR 
TEST SYSTEMS

Aehr Test Systems - WW Customer Base



Over 2500 systems shipped Worldwide!

(Partial Customer List)



Market Drivers

- **Automotive IC growth** in sensors, control, information, and entertainment has substantially higher requirements for initial quality and long term reliability
- **Mobility smartphone and tablets** drive increased test, quality, reliability, and environmental demands
- **Shrinking process nodes** of advanced ICs driving more leakage and power variance impacting reliability and test technology
- Ever increasing **pressure on cost of test** driving massive parallelism and design for test requirements at wafer level and package test



Aehr Test Product Families

ABTS

**Packaged Part Test
& Burn-in Systems**



**Cost-effective, reliable
and highly configurable
Test & Burn-in Systems**



**Multiple Wafer Test
& Burn-in Systems
and Contactors**



**Unique solution for test
& burn-in for KGD and
automotive applications**



**Single Wafer Test
& Burn-in Systems
and Contactors**



**Reduced cost of test
with high throughput
parallel test at wafer
probe**



Addressing Test & Burn-in Needs



ABTS-L

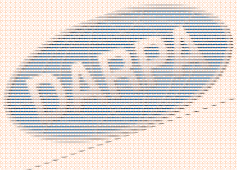
ABTS Family of Packaged Part Test & Burn-in Systems

- 13 Customers on New Platform
- Automotive, Mobile Processors, Video/Graphics, 4G Comms, & High Power SOCs
- Proprietary family of high performance thermal chambers
- Turn-key solution for individual temperature control of each device under test



Full-Wafer Test Evolution

Systems



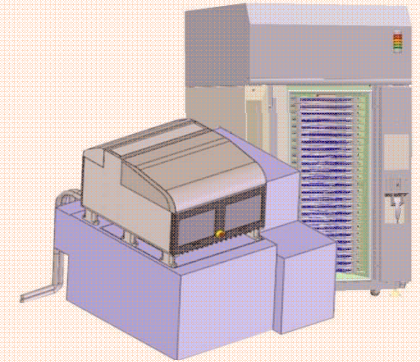
14 200mm Wafer Slots
Air thermal control
Full Algo PG



Single 300mm Wafer
Liquid Cooled
Full Algo or JTAG/BIST



15 300mm Wafer Slots
Liquid Thermal Control
Vector or Algo PG



Single/Multi 300mm Wafer
Liquid /Air Cooled
Vector with JTAG/BIST

1995

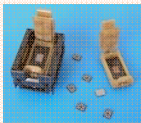
2002

2006

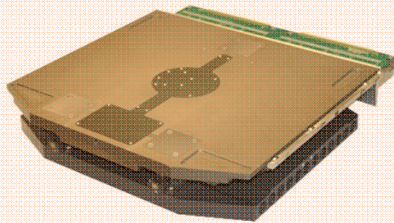
2009

2014

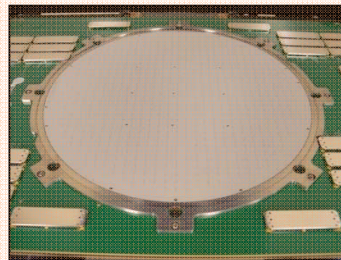
Contactors



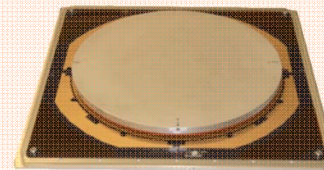
Single Die



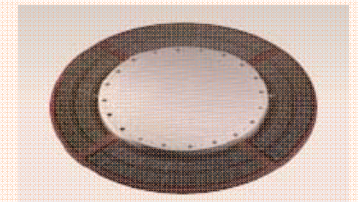
200mm Wafer



300mm Wafer



300mm Wafer



300mm Wafer



Multi-Wafer Test & Burn-in

- **Cost-effective Solution for Producing Known-Good-Die (KGD)**
 - Stacked and Multi-Chip Packages
 - Zero-defect tolerant applications
- **Production Proven Full-Wafer Burn-in Solution**
 - Protects wafers and probe cards with individual power channel over-current protection
 - High volume production capacity
 - Highly reliable – 3rd generation design
- **Reduces Costs:**
 - Improves yield on Stacked and Multi-Chip Package Devices
 - Reduces wafer sort and final test costs by allowing functional test to be done at burn-in



Aehr: Positioned for Growth

- Aehr has solid IP, technology, and products and a large installed base of most of the largest semi companies
- Introduced new products that are highly competitive and address new market segments
- Test trends driven by mobility, automotive, and advanced process shrinks are moving towards Aehr Test's strengths and product offerings
- Targeting significant new opportunities and market segments with wafer level and package part test market with FOX and ABTS test & burn-in products